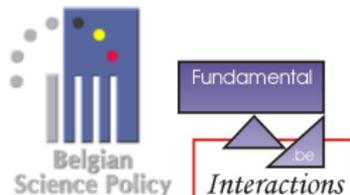


Pixel detector developments

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Introduction

Particle Physics and Experimental Methods
Technology Review (HAPSvsMAPS)

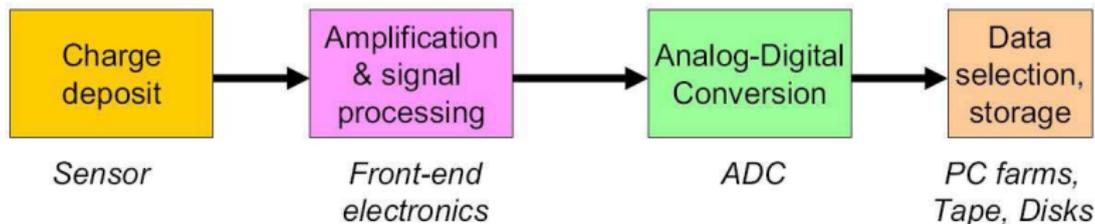
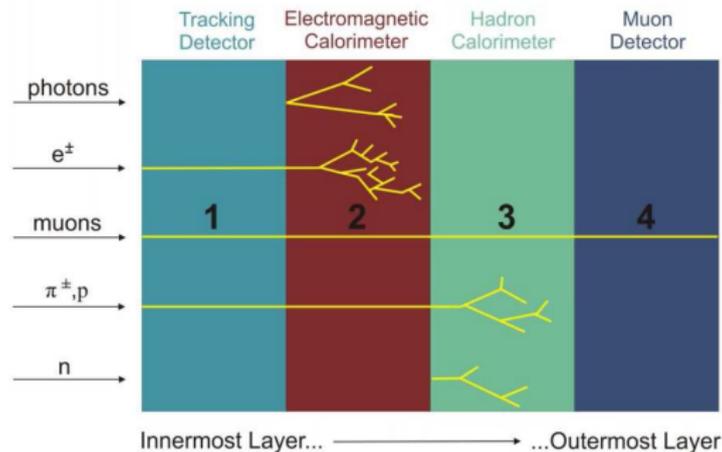
SOI pixel project: TRAPPISTe

Technological Details
Simulations

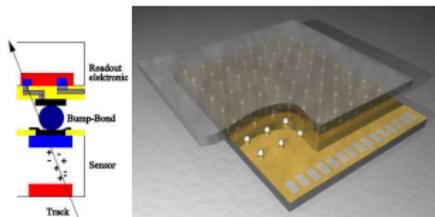
NA62: Measurement of rare decay

Characteristics
ASIC development for the readout electronics of the GTK





HAPS Hybrid Active Pixel Sensor



Sensor and FE chip connected through

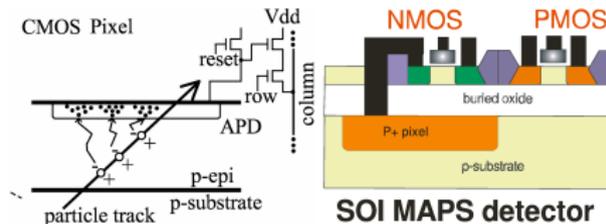
- ▶ Bump bonding, flipchip

Architecture used:

- ▶ LHC-collider :ALICE, ATLAS, CMS and LHCb
- ▶ Fixed target: NA60, BTev



Monolithic Pixel Detectors



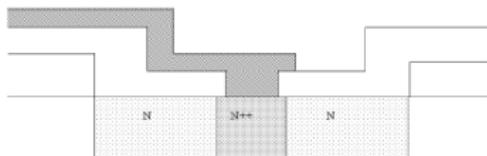
Include amplifying, logic and detecting sensors as one entity

Non-standard CMOS on high resistivity bulk CMOS with epi-layer, CMOS on SOI, Amorphous silicon on standard CMOS ASIC, DEPFET, Deep n-well sensor, 3D packaging

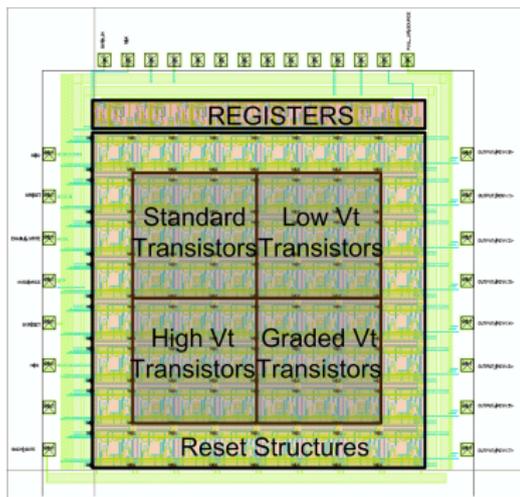
TRAPPISTe-1 (TRACKing Particle for Physics Instrumentation in SOI Technology)

- ▶ R&D project for the study of the feasibility to build a Monolithic Active Pixel Sensor (MAPS) with Silicon On Insulator (SOI)
- ▶ First prototype has been built with a $2\mu\text{m}$ technology in SOI production facility in Louvain-la-Neuve



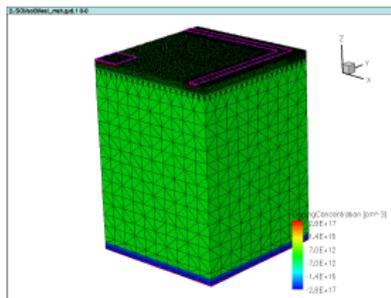


A hole is created in the buried oxide layer to dope the bulk layer P-type bulk with n+ region
Not covered in metal to allow top illumination



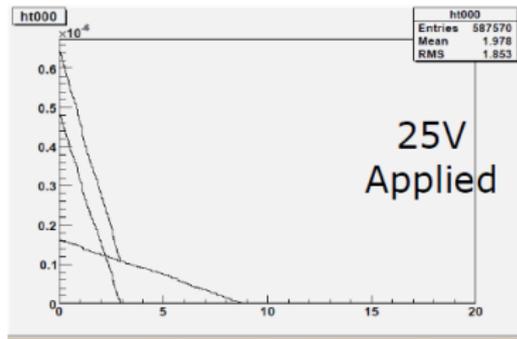
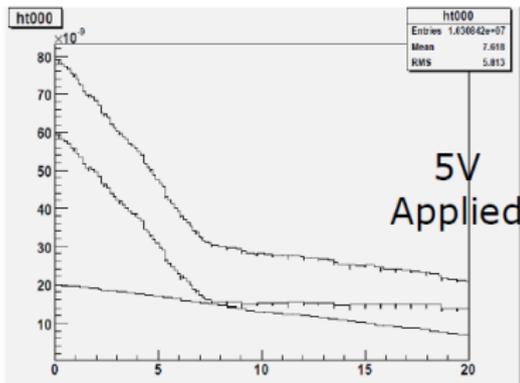
Area_{prototype} = $3150 \times 3150 \mu\text{m}$,
with matrix of 8×8 pixels with
a size of $300 \times 300 \mu\text{m}$
An external ring of pixels will
be grounded for a better
isolation

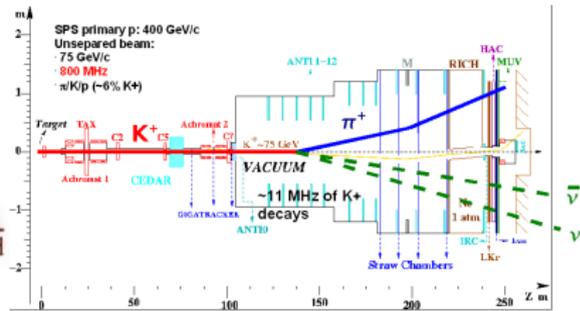




- ▶ Depleted region \Rightarrow carrier drift
- ▶ Non-depleted region \Rightarrow carrier diffusion
- ▶ Always trapping and recombination

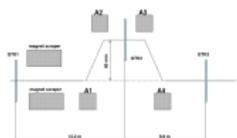
An initial rough estimate of the current signal (thickness of $100\mu\text{m}$ and a resistivity of $5000\Omega/\text{cm}$.)



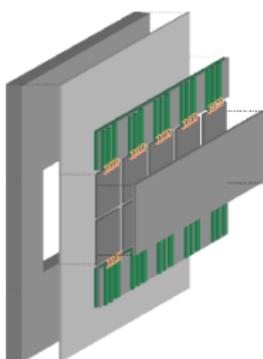


Rare Kaon Decays program at CERN, Measurement of $K^+ \rightarrow \pi^+ \nu \bar{\nu}$





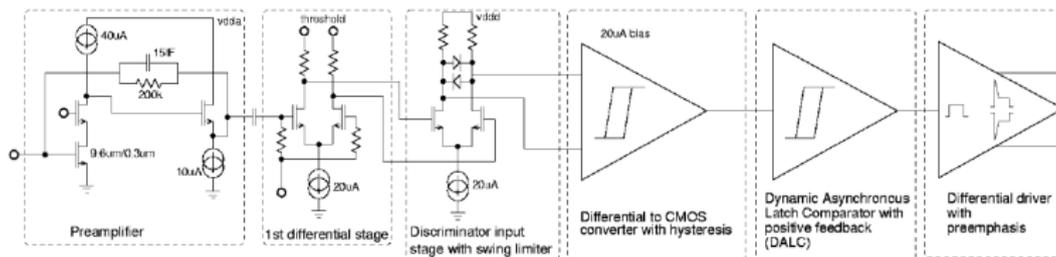
- ▶ 3 stations with area $\sim 12 \text{ cm}^2$ each \rightarrow 18000 pixels/station and 2 rows \times 5 columns pixels/station
- ▶ Pixel dimensions $300 \times 300 \mu\text{m}$ \rightarrow 1800 pixels/chip
- ▶ Radiation levels expected 10^5 Gy and the 1 MeV neutron equivalent fluence $\sim 2 \times 10^{14} \text{ cm}^{-2}/\text{year}$.
- ▶ Very low material budget of $0.45 \% X_0$
- ▶ Thickness \rightarrow ASIC: $100 \mu\text{m}$, silicon sensor: $150\text{-}200 \mu\text{m}$
- ▶ Analogue FE sensitivity discrimination threshold $\sim 0.5 \text{ fC}$.
- ▶ Ultra fast analogue FE with $t_{peaking} \sim 3\text{-}5 \text{ ns}$



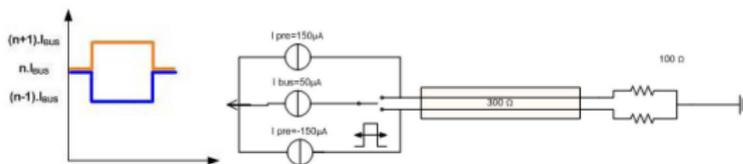
Specifications of this detector:

- ▶ Time resolution of GTK(rms)150ps, of one station(rms)200ps
- ▶ Particle rate/station 800 MHz, Particle rate/chip 130MHz
- ▶ Average particle intensity/station 0.5 MHz/mm², Peak hit rate of 50 Mhits/cm²/s
 - ▶ **One order of magnitude faster than pixel LHC ASIC**
- ▶ Latency >1μs up to 1ms, with trigger window ≥ 10 ns
- ▶ Dead time due to read out 1% (2% in beam center)
- ▶ Power dissipation per station ≤ 2W/cm², 32 W
- ▶ Operating temperature vacuum < 0 °C





Input stage with cascode-stage ($40\mu\text{A}$) and a $R_{feedback} = 200\text{k}\Omega$
 TL (GHz bandwidth) driven with current mode pre-emphasis
 $I_{Bias\ analogue\ pixel\ channel} = 120\mu\text{A}$ and $I_{Bias\ TL\ driver} = 80\mu\text{A}$
 $\text{Gain}_{FE\ amplifier} \sim 70\text{mV/fC}$,
 $V_{offset, simulated\ mismatch} \sim 6\text{mV}_{rms} (\sim 0.1\text{fC signal})$,
 $\text{TW}_{comparator} (Q_{threshold} = 0.7\text{fC}) = 11.5\text{ns}$ between 1 and 4fC signal



Logic level $\pm 50\mu\text{A}$ on $250\mu\text{A}$ bus bias current; right lossy transmission lines driven with pre-emphasis

Timing precision of low power signal transmission down to the EOC circuits, with 45 TL (driven in current mode)

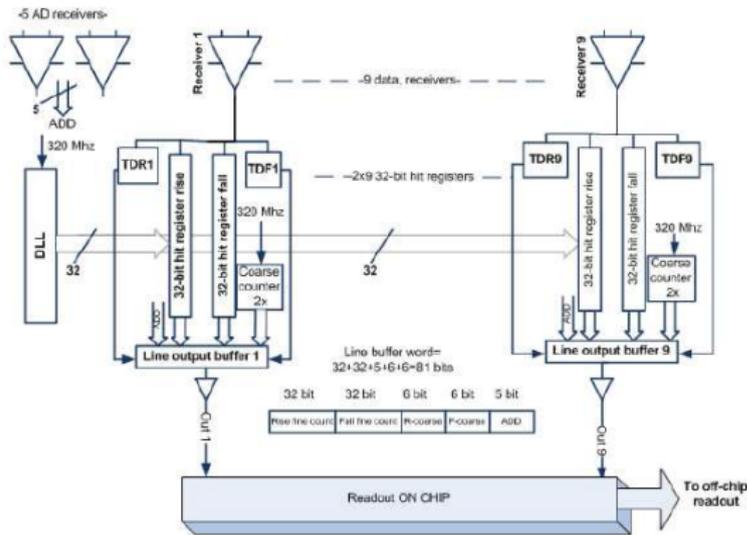
- ▶ I_{driver} is differential switch with equalization
- ▶ $V_{sensing\ at\ far-end} = 0\text{mV}$ for $R_{receiver\ input} = 100\Omega$
- ▶ $R_{line\ for\ 1-45\ pixel\ distance} = 6-30\Omega$, with $V_{max\ drop} = 3 \times V_{sensing}$

Far end amplitude does not change with receiver distance

Receiver:

- ▶ Input stage circuit to sense $I_{differential}$, $I_{static} \sim 250\mu\text{A}$
- ▶ Broadband differential to single ended amplifier stage
- ▶ Generates pulses edges of 50ps to TDC inputs.





End of column circuitry:
 Receiver bank, TDC bank,
 Address encoding circuits and
 Digital logic for processing the
 hit data ready for transmission
 off chip.
 32-bit DLL and one PLL
 providing a 320MHz clock
 signal for the DLL are common
 to all end of line circuits.

Each TDC presents 2 32-bit hit registers

- ▶ Leading and trailing edge of the hit \Rightarrow double time stamping
- ▶ Time stamps encoded into 5-bit binary words, stored in a line buffer, serialized and sent off chip

